

FAST CMOS 18-BIT REGISTER

IDT74FCT162823AT/CT

FEATURES:

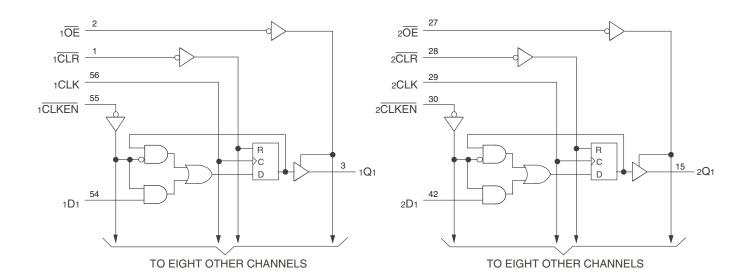
- 0.5 MICRON CMOS Technology
- · High-speed, low-power CMOS replacement for ABT functions
- Typical tsk(o) (Output Skew) < 250ps
- Low input and output leakage ≤1µA (max.)
- Vcc = 5V ±10%
- · Balanced Output Drivers of ±24mA
- · Reduced system switching noise
- Typical Volp (Output Ground Bounce) < 0.6V at Vcc = 5V, TA = 25°C
- · Available in SSOP and TSSOP packages

DESCRIPTION:

The FCT162823T 18-bit bus interface register is built using advanced, dual metal CMOS technology. These high-speed, low-power registers with clock enable ($x\overline{\text{CLKEN}}$) and clear ($x\overline{\text{CLR}}$) controls are ideal for parity bus interfacing in high-performance synchronous systems. The control inputs are organized to operate the device as two 9-bit registers or one 18-bit register. Flow-through organization of signal pins simplifies layout. All inputs are designed with hysteresis for improved noise margin.

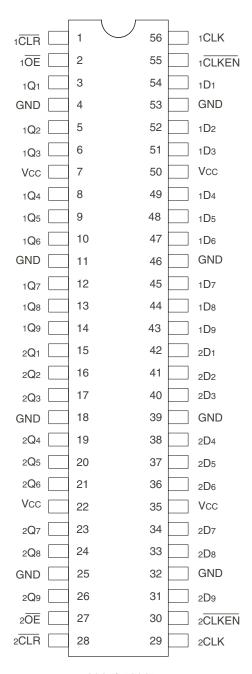
The FCT162823T has balanced output drive with current limiting resistors. This offers low ground bounce, minimal undershoot, and controlled output fall times – reducing the need for external series terminating resistors. The FCT162823T is a plug-in replacement for the FCT16823T and ABT16823 for on-board interface applications.

FUNCTIONAL BLOCK DIAGRAM



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PIN CONFIGURATION



SSOP/ TSSOP TOP VIEW

ABSOLUTE MAXIMUM RATINGS(1)

Symbol	Description	Max	Unit
VTERM ⁽²⁾	Terminal Voltage with Respect to GND	-0.5 to 7	V
VTERM ⁽³⁾	Terminal Voltage with Respect to GND	-0.5 to Vcc+0.5	V
Tstg	Storage Temperature	-65 to +150	°C
lout	DC Output Current	-60 to +120	mA

NOTES:

- 1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- 2. All device terminals except FCT162XXX Output and I/O terminals.
- 3. Outputs and I/O terminals for FCT162XXX.

CAPACITANCE (TA = +25°C, f = 1.0MHz)

Symbol	Parameter ⁽¹⁾	Conditions	Тур.	Max.	Unit
CIN	Input Capacitance	VIN = 0V	3.5	6	pF
Соит	Output Capacitance	Vout = 0V	3.5	8	pF

NOTE

1. This parameter is measured at characterization but not tested.

PIN DESCRIPTION

Pin Names	Description		
хDх	DataInputs		
xCLK	Clock Inputs		
xCLKEN	Clock Enable Inputs (Active LOW)		
xCLR Asynchronous clear Inputs (Active LOW)			
xŌĒ	Output Enable Inputs (ActiveLOW)		
хОх	3-State Outputs		

FUNCTION TABLE(1)

	Inputs					
хŌЕ	xCLR	xCLKEN	xCLK	хDх	хОх	Function
Н	Х	Χ	Χ	Χ	Z	High Z
L	L	Χ	Χ	Χ	L	Clear
L	Н	Н	Χ	Χ	Q ⁽²⁾	Hold
Н	Н	L	1	L	Z	Load
Н	Н	L	1	Н	Z	
L	Н	L	1	L	L	
L	Н	L	1	Н	Н	

- 1. H = HIGH Voltage Level
 - L = LOW Voltage Level
 - X = Don't Care
 - Z = High-Impedance
- 2. Output level before indicated steady-state input conditions were established.

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

 $Following \ Conditions \ Apply \ Unless \ Otherwise \ Specified:$

Industrial: TA = -40°C to +85°C, VCC = $5.0V \pm 10\%$

Symbol	Parameter	Test Condition	ns ⁽¹⁾	Min.	Тур. ⁽²⁾	Max.	Unit
VIH	Input HIGH Level	Guaranteed Logic HIGH Level		2	_	1	V
VIL	Input LOW Level	Guaranteed Logic LOW Level		_	_	0.8	V
Iн	Input HIGH Current (Input pins)(4)	Vcc = Max.	VI = VCC	_	_	±1	μA
	Input HIGH Current (I/O pins)(4)			_	_	±1	
lıL	Input LOW Current (Input pins)(4)]	VI = GND	_	_	±1	
	Input LOW Current (I/O pins)(4)			_	_	±1	
lozh	High Impedance Output Current	Vcc = Max.	Vo = 2.7V	_	_	±1	μA
lozL	(3-State Output pins) ⁽⁴⁾		Vo = 0.5V	_	_	±1	
Vik	Clamp Diode Voltage	Vcc = Min., IIN = -18mA		_	-0.7	-1.2	V
los	Short Circuit Current	Vcc = Max., Vo = GND ⁽³⁾		-80	-140	-250	mA
VH	Input Hysteresis	_		_	100	_	mV
ICCL	Quiescent Power Supply Current	Vcc = Max		_	5	500	μА
Іссн		Vin = GND or Vcc					
Iccz							

OUTPUT DRIVE CHARACTERISTICS

Symbol	Parameter	Test Condi	Test Conditions ⁽¹⁾		Typ. ⁽²⁾	Max.	Unit
IODL	Output LOW Current	$VCC = 5V$, $VIN = VIH or VIL$, $VO = 1.5V^{(3)}$		60	115	200	mA
IODH	Output HIGH Current	VCC = 5V, $VIN = VIH or VIL$, $VO = 1.5V$	$VCC = 5V$, $VIN = VIH or VIL$, $VO = 1.5V^{(3)}$		-115	-200	mA
Vон	Output HIGH Voltage	Vcc = Min.	Iон = -24mA	2.4	3.3	_	V
		VIN = VIH or VIL					
Vol	Output LOW Voltage	Vcc = Min.	IOL = 24mA	_	0.3	0.55	٧
		VIN = VIH or VIL					

- 1. For conditions shown as Min. or Max., use appropriate value specified under Electrical Characteristics for the applicable device type.
- 2. Typical values are at Vcc = 5.0V, +25°C ambient.
- 3. Not more than one output should be shorted at one time. Duration of the test should not exceed one second.
- 4. This test limit for this parameter is $\pm 5\mu A$ at $T_A = -55^{\circ}C$.

POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
Δlcc	Quiescent Power Supply Current TTL Inputs HIGH	VCC = Max. $VIN = 3.4V(3)$		_	0.5	1.5	mA
ICCD	Dynamic Power Supply Current ⁽⁴⁾	Vcc = Max. Outputs Open xOE = xCLKEN = GND One Input Toggling 50% Duty Cycle	VIN = VCC VIN = GND	_	75	120	μΑ/ MHz
Ic	Total Power Supply Current ⁽⁶⁾	Vcc = Max. Outputs Open fcP = 10MHz 50% Duty Cycle	VIN = VCC VIN = GND	_	0.8	1.7	mA
		xOE = xCLKEN = GND at fi = 5MHz 50% Duty Cycle One Bit Toggling	VIN = 3.4V VIN = GND	_	1.3	3.2	
		Vcc = Max. Outputs Open fcP = 10MHz 50% Duty Cycle	VIN = VCC VIN = GND	_	4.2	7.1 ⁽⁵⁾	
		xOE = xCLKEN = GND at fi = 2.5MHz 50% Duty Cycle Eighteen Bits Toggling	VIN = 3.4V VIN = GND	_	9.2	22.1 ⁽⁵⁾	

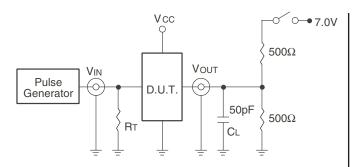
- 1. For conditions shown as Min. or Max., use appropriate value specified under Electrical Characteristics for the applicable device type.
- 2. Typical values are at Vcc = 5.0V, +25°C ambient.
- 3. Per TTL driven input ($V_{IN} = 3.4V$). All other inputs at Vcc or GND.
- 4. This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
- 5. Values for these conditions are examples of the Icc formula. These limits are guaranteed but not tested.
- 6. IC = IQUIESCENT + INPUTS + IDYNAMIC
 - $IC = ICC + \Delta ICC DHNT + ICCD (fcpNcp/2 + fiNi)$
 - Icc = Quiescent Current (IccL, IccH and Iccz)
 - Δ Icc = Power Supply Current for a TTL High Input (VIN = 3.4V)
 - DH = Duty Cycle for TTL Inputs High
 - NT = Number of TTL Inputs at DH
 - ICCD = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)
 - fcp = Clock Frequency for Register Devices (Zero for Non-Register Devices)
 - NCP = Number of Clock Inputs at fcP
 - fi = Input Frequency
 - Ni = Number of Inputs at fi

SWITCHING CHARACTERISTICS OVER OPERATING RANGE

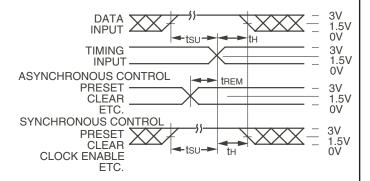
			FCT162	823AT	FCT162	823CT	
Symbol	Parameter	Condition ⁽¹⁾	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Unit
tplh	Propagation Delay	CL = 50pF	1.5	10	1.5	4.7	ns
tphl	xCLKx to xOx	$RL = 500\Omega$					
		$CL = 300pF^{(4)}$	1.5	20	1.5	8	
		$RL = 500\Omega$					
tphl	Propagation Delay	CL = 50pF	1.5	14	1.5	4.7	ns
	xCLR to xQx	$RL = 500\Omega$					
tpzh	Output Enable Time	CL = 50pF	1.5	12	1.5	4.4	ns
tpzL	xOE to xOx	$RL = 500\Omega$					
		$CL = 300pF^{(4)}$	1.5	23	1.5	9	
		$RL = 500\Omega$					
tphz	Output Disable Time	$CL = 50pF^{(4)}$	1.5	7	1.5	3.6	ns
tPLZ	x OE to xOx	$RL = 500\Omega$					
		CL = 50pF	1.5	8	1.5	3.6	
		$RL = 500\Omega$					
tsu	Set-up Time HIGH or LOW xDx to xCLK	CL = 50pF	3	_	1.5	_	ns
		RL= 500Ω					
tH	Hold Time HIGH or LOW, xDx to xCLK		1.5	_	0	_	ns
tsu	Set-up Time HIGH or LOW, xCLKEN to xCLK		3	_	2.5	_	ns
tH	Hold Time HIGH or LOW, xCLKEN to xCLK		0	_	0	_	ns
tw	xCLK Pulse Width HIGH or LOW		6	_	3	_	ns
tw	xCLR Pulse Width LOW		6	_	3	_	ns
trem	Recovery Time, xCLR to xCLK		6	_	3	_	ns
tsk(o)	Output Skew ⁽³⁾		_	0.5	_	0.5	ns

- 1. See test circuit and waveforms.
- 2. Minimum limits are guaranteed but not tested on Propagation Delays.
- 3. Skew between any two outputs, of the same package, switching in the same direction. This parameter is guaranteed by design.
 4. This condition is guaranteed but not tested.

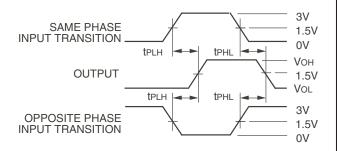
TEST CIRCUITS AND WAVEFORMS



Test Circuits for All Outputs



Set-up, Hold, and Release Times



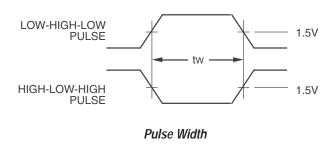
Propagation Delay

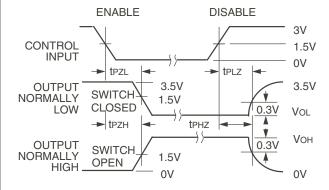
SWITCH POSITION

Test	Switch
Open Drain Disable Low Enable Low	Closed
All Other Tests	Open

DEFINITIONS:

- $\ensuremath{\text{CL}}$ = Load capacitance: includes jig and probe capacitance.
- RT = Termination resistance: should be equal to ZouT of the Pulse Generator.

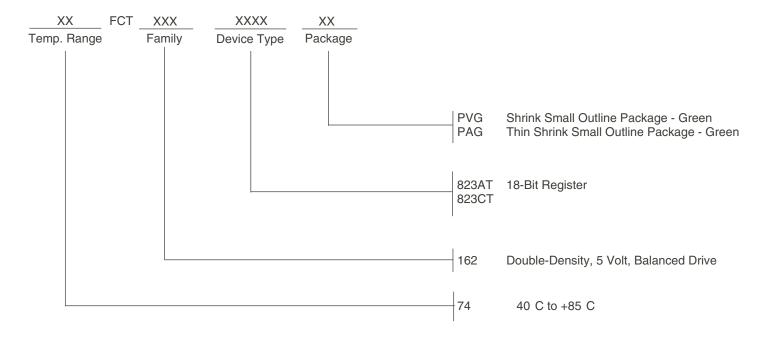




Enable and Disable Times

- 1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.
- 2. Pulse Generator for All Pulses: Rate \leq 1.0MHz; tr \leq 2.5ns; tr \leq 2.5ns.

ORDERING INFORMATION



Datasheet Document History

09/06/09 Pg. 7 Updated the ordering information by removing the "IDT" notation and non RoHS part.

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